

## Search Notes



## Application/Control No.

10/779,593

## Examiner

Scott R. Wilson

## Applicant(s)/Patent under Reexamination

JAYAPALAN ET AL.

## Art Unit

2826

SEARCHED			
Class.	Subclass	Date	Examiner
257	48 E21, 524 <del>324</del>	5/18/05	Sum
	3		
331	105		
324	500 537		
	750		
	763		
	765		
	555		
	600		
	612		
	649		
	654		
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	657		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	5/18/05	Sum
google "measurement parasitic inductance effects"	5/18/05	Sum
on-chip "		
INSPEC NPL "measurement ADJ parasitic ADJ inductance"	5/18/05	Sum

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner